

Extending HELIPORT for Clean Room Process Tracking at HZDR

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HELIPORT Workshop 2023

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- Sample processing in Cleanroom at HZDR
- Prototype Implementation (HELIPORT)
- Outlook: Future steps and ideas

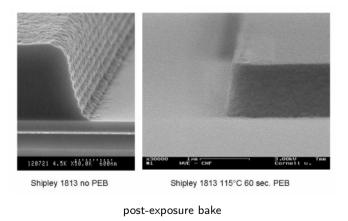


Nanofabrication in Cleanroom at HZDR

- Similar to microchip production
- Custom processes
- Written plans
- Things can break
- Equipment for each step



Photonic device [4]





Process logs

- Sample passed around together with Paper
- Entries for each step
- Current step is first one without signature
- Project, sample series, sample number
- Manually transferred to wiki

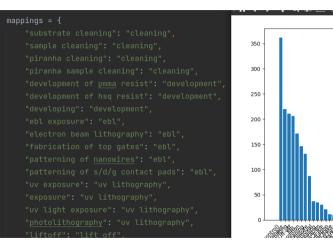
Post-exposure bake	
- Bake at 120°C 2 min for resist refl	100 20.04.21 . CF
Oxide etching	,
Bottled BOE (buttered oxide etch) Measured thickness = <u>JOC</u> r Etch time = <u>JOC</u> see All oxide is stothed when backaid Rinse heavily in DI water at chereit	nm 1m30s
Lift-off	12.5.21 G.S
Adetone 1, utrasonic bath 5 minus Adetone 2, utrasonic bath 5 minus Ethanol trins, 1 minus Di water wash Spin drip (IBPS Spin Dryer)] Skrwly accelerate (rom 0 to 3000 Dry at 3000 rpm for 1 minute Visually confirm the transfer of excit	0 12.5.216.5
Spin negative resist for UV L	Ithography - V2
 spin negative photoresist [[Cleaning Baking et 100*C for 2 minutes on 	com Chemicals maN1400jmaN1420jj at 2000rpm for 30s 12.
UV Lithography	
Exposure of NCP Mask 2 - Contact Vacuum of Hard contact for 10 set Lamp Intensity – 20, mW/cm	ct pads and alignment system Sopt contact, 10, conds *1.295 W
Development	
- Developed in maD533s for 1m15s	1 12.05.71 CF

post-exposure bake



Automation is Difficult

Example: Find most common steps

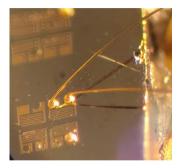


Mapping titles and histogram of most common step types



Automatic Information Processing

- Search
- Statistics
- Error detection scripts
- Show progress
- $\blacksquare \Rightarrow \mathsf{Paperless} \text{ process tracking}$
- ELN based on MediaWiki [5]





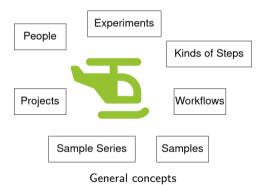
Gold Wirebonds

Piranha cleaning



Relation to HELIPORT

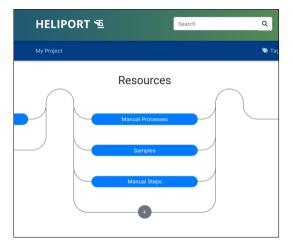
- HELIPORT is not for detailed experimental data
- A lot of high-level information relevant
- Use Digital Object concept in HELIPORT
- Interaction with other Systems





Current State

- What is needed?
- How could it be achieved?
- Look through existing Processes
- Prototype



Project graph with Samples / Workflows



Samples

- Workflows and samples go together
- Sample as entry point for taking actions
- Different actions possible based on context e.g. currently performing workflow
- Relation workflows and samples

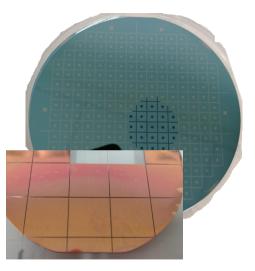
HELIPORT 🖻	Search	Q
Test Project 📏 Samples 📏 higł	🔊 Ta	
Relation Properties	(with autocomplete)	advanced editing
Project	Nano-Contact Platform	
Sample Series	highly-doped Si	
Substrate Material	Si	
Substrate orientation	100	

Sample Description



Collections of Samples

- Step on collection = step on each sample
- Reduces management overhead
- Cutting can create collections



Wafers are cut



Process History

- This is the main goal
- Who did what where and when?
- What plans / steps were performed?
- What were the parameters?
- What were the measured values?

highly-doped Si 2021-2			
Name: Voigt, Martin (FWCC-D) - 141575 E-mail: m.voigt@hzdr.de Phone: 1234		te: Fowley, Dr. Ciasan (FWIO-F) - 6176 all: c.fowley@hzdr.de Phone: 3253	
roject: Nano-Contact Platform	Sample Series: highly-doped S	Sample Number: 2021-2	
Substrate Material: Si	Substrate orientation: 1 0 0	Substrate thickness: $525 \ \mu m$	
Apping: Resistivity 1-5 mOhm.cm	Dimensitions: 100 mm		Toggle Fun.
Oxide exhing			
 Bottled BOE (buffered oxide etch) ~ 90 	nmmin		
Measured thickness = nm			
Each time = sec			
All colde is etched when backside of w Rinse heavily in DI water at chemistry			
Equipment used			
Done			
			Toggle P
6. Post-exposure bake 🖌		L Fowley, Dr. Ciaran (FWID-F) - 6176	O Jun 09, 23
Bake at 320°C 2 min for resist reflow			
5. Development 🗸		🚊 Fowley, Dr. Ciaran (FWIO-F) - 6176	O Jun 09, 23
Develop in [WF-319] for 45s			
 DI water stopper Spin dry in ISPS Spin Dryer! 			
 3000 rpm for 1 minute 			
Equipment used None			
4. UV Lithography 🖌		L Fowley, Dr. Ciasan (FWIO-F) - 6176	O Jun 09, 23
Exposure of NCP Mask 1 - Demarcatic Soft contact for 3 seconds	on to define SiO ₂ etching pattern		
Lamp intensity = 20 mNRom ¹ (324 W		
Equipment used MAB			
3. Spin positive photoresist for UV Lithograp	tıy 🗸	L Fowley, Dr. Claran (FWIO-F) - 6176	O Jin 09, 23

Process history



Manual Workflows

- Typically linear sequence of steps
- Basic looping and branching (user selects alternative step)
- Sub Recipes
- Merge similar consecutive steps
- Workflow with all parameters specified (template → instance → execution)

Exposure of NCP Mask 2 - Contact Vacuum of Hard contact for 10 seco Lamp Intensity =, mW/cm ²	pads and alignment system Sopt contacts
Development	
Developed in maD533s for 1m15s Di water stopper Spin dry in [[SPS Spin Dryer]] Slowly accelerate from 0 to 3000 Dry at 3000 rpm for 1 minute	12.05.71 CF 10.30s/10.45s/400
Deposition	Λ.
- Deposition 5nm Cr / 125nm Au - Rates = , Z., Ang/s, S., Ang/s - Thickness = S., nm, M., nm	205.21 filla.
Lift-off	14/00/2 CF
Acetone 1 in ultrasonic bath, 5 min. Acetone 2 in ultrasonic bath, 5 min. Ethanol rinse, 1 minute Di water wash Spin dry in [[SPS Spin Dryer]] Sidw accelerate from 0 to 3000	ltes

Merged Deposition Steps



The current Prototype - Implementation

- HeliportObjectListView: Typical heliport lists
 - WorkflowsView
 - SamplesView
 - ManualActionsView
- WorkflowDetailView: Workflow editing
- ActionPerformView: Select workflow for sample
- SampleLogView: Workflow execution and log
- SampleMetadataView: Show/Edit sample metadata

HELIF	PORT 🖻	Search	Q i About 🛛 Docs 💄 mv141575 -
Test Project	t 🕻 Manual Processes		🕲 Tags 🕚 Project Timeline 🛛 🐄 Object Graph 🔹 Project 👻
Proces	ses		
ID	Name	Description	
2	CF NCP Fabrication 2021-2 Zahra 90nm	Si; 525µm; 100	Add Tag Open Plan for Edit Delete
Add a ne	ew Process		
Name			
Description	n		
Add			

Workflow List



Metadata Export

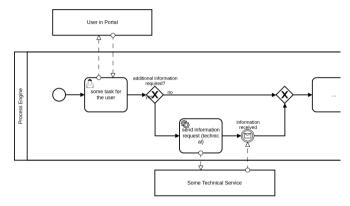
HELIPOR	रा 🗉	Search	Q		🖻 Docs	💄 eilmiv 👻
Landing Page						
Lidentifier	Metadata Expor Select Metadata Form Datacite JSON Datacite XML JSON-LD Turtle					
Identifier Namespace Properties	RDF XML N-Triples Default Landing Pag Specific Landing Pa		bject/51/			
label	CF NCP	Fabrication 2021-2 Zahr	a 90nm		Not Publi	c ~
description	Si; 525µ	m; 100			Not Public	c ~
Date Created	Mar 16, :	2023			This attribute	is always



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Metadata Standards - BPMN

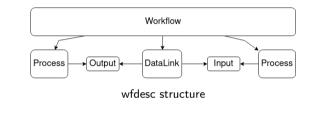
- Focus on modeling and notation
- Execution semantic
- Very expressive
- Workflow engines
 - Camunda [2]
 - python libraries [3]
- RDF ontology exists [1]



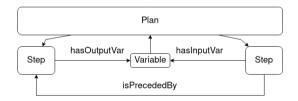




Metadata Standards - wf4ever / p-plan



- Workflow execution provenance
- Directed acyclic data flow graphs
- Subworkflows
- Specify order in p-plan



p-plan structure



Generalisation

Manual workflows

- Generalize from physical steps
- Generally useful
- Enable using standard without knowing (workflow sets metadata)
- complement existing automatic workflows with manual steps

Samples

- Generalize from cleanroom samples
- Generally useful
- Basic abstraction for integrating sample management systems



References

- Amina Annane, Nathalie Aussenac-Gilles, and Mouna Kamel. "BBO: BPMN 2.0 based ontology for business process representation". In: 20th European Conference on Knowledge Management (ECKM 2019). Vol. 1. 2019, pp. 49–59.
- [2] BPMN Examples. CAMUNDA. URL: https://camunda.com/bpmn/examples/.
- [3] BPMN-RPA. PyPl. URL: https://pypi.org/project/BPMN-RPA/.
- [4] Michael Hollenbach et al. "Wafer-scale nanofabrication of telecom single-photon emitters in silicon". In: Nature Communications 13.1 (2022), p. 7683.
- [5] Semantic MediaWiki. MediaWiki. URL: https://www.semantic-mediawiki.org/wiki/Semantic_MediaWiki.

